

MOS FIELD EFFECT TRANSISTOR μ PA1870

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1870 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1870 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5-V power source
- · Low on-state resistance

 $R_{DS(on)1}$ = 20.0 $m\Omega$ MAX. (Vgs = 4.5 V, Ip = 3.0 A)

 $R_{DS(on)2} = 21.0 \text{ m}\Omega \text{ MAX.}$ (Vgs = 4.0 V, ID = 3.0 A)

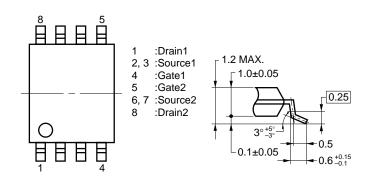
 $R_{DS(on)3} = 27.0 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 2.5 \text{ V, ID} = 3.0 \text{ A)}$

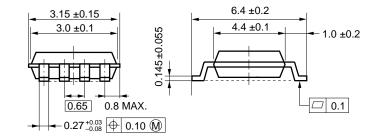
· Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1870GR-9JG	Power TSSOP8

PACKAGE DRAWING (Unit: mm)

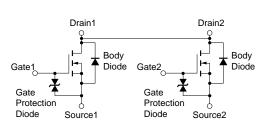




ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Voce	20	V
V D55	20	V
Vgss	±12	V
ID(DC)	±6.0	Α
D(pulse)	±80	Α
Рт	2.0	W
Tch	150	°C
Tstg	-55 to +150	°C
	ID(DC) ID(pulse) PT Tch	VGSS ±12 ID(DC) ±6.0 ID(pulse) ±80 PT 2.0 Tch 150

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Mounted on ceramic substrate of 50 cm² x 1.1 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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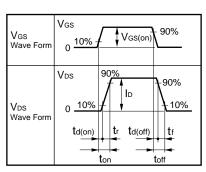


ELECTRICAL CHARACTERISTICS (TA = 25°C)

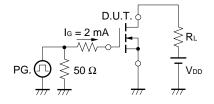
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	loss	V _{DS} = 20 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	$V_{GS} = \pm 12 V, V_{DS} = 0 V$			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	0.5	1.0	1.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 3.0 A	5			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 4.5 V, ID = 3.0 A	12.0	15.0	20.0	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 3.0 A	13.0	15.5	21.0	mΩ
	RDS(on)3	Vgs = 2.5 V, ID = 3.0 A	15.0	20.8	27.0	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		900		pF
Output Capacitance	Coss	Vgs = 0 V		295		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		170		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 10 V, I _D = 3.0 A		55		ns
Rise Time	tr	V _{GS(on)} = 4.0 V		210		ns
Turn-off Delay Time	t _{d(off)}	$R_G = 10 \Omega$		300		ns
Fall Time	t _f			340		ns
Total Gate Charge	Q _G	V _{DD} = 16 V		10		nC
Gate to Source Charge	Qgs	Vgs = 4.0 V		2		nC
Gate to Drain Charge	Q _{GD}	ID = 6.0 A		6		nC
Body Diode Forward Voltage	V _F (S-D)	IF = 6.0 A, VGS = 0 V		0.80		V
Reverse Recovery Time	trr	IF = 6.0 A, VGS = 0 V		400		ns
Reverse Recovery Charge	Qrr	$di/dt = 50 A/\mu s$		1000		nC

TEST CIRCUIT 1 SWITCHING TIME

PG. \square R_{G} 0 $\tau = 1 \mu s$ Duty Cycle $\leq 1\%$

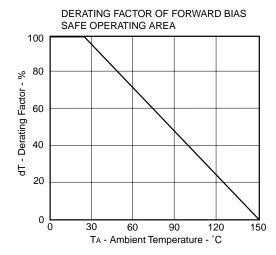


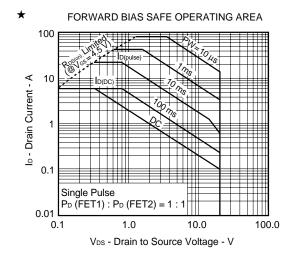
TEST CIRCUIT 2 GATE CHARGE

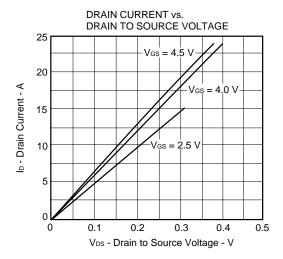


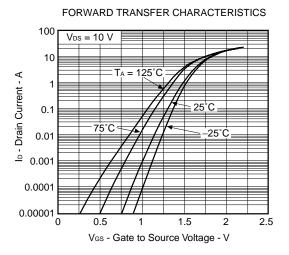


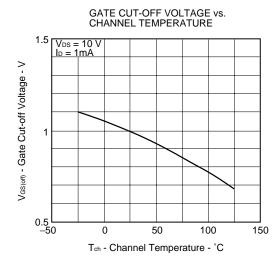
TYPICAL CHARACTERISTICS (TA = 25°C)

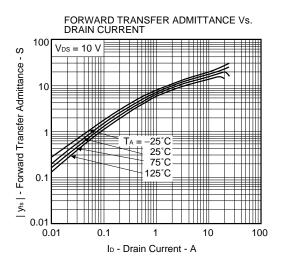






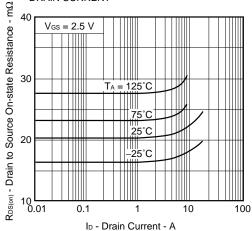




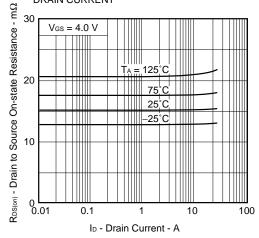


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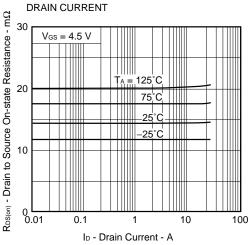
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



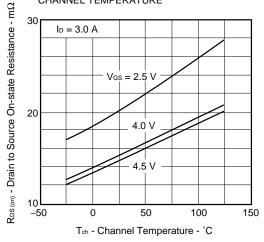
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



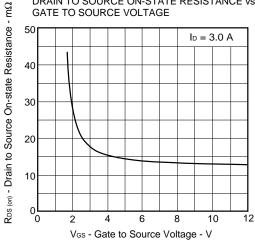
DRAIN TO SOURCE ON-STATE RESISTANCE vs.

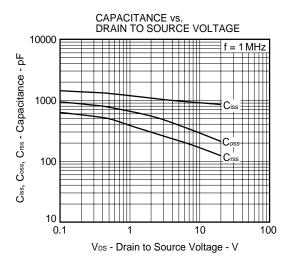


DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



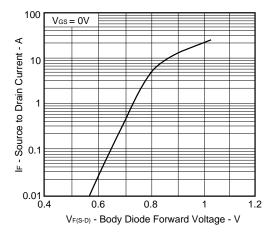
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



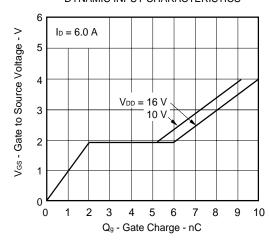


SWITCHING CHARACTERISTICS 1000 Su tal(off) tr tr VDD = 10 V VGS(on) = 4 V RG = 10 Ω Ib - Drain Current - A

SOURCE TO DRAIN DIODE FORWARD VOLTAGE



DYNAMIC INPUT CHARACTERISTICS



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TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH 1000 100 100 Single Pulse Mounted on Ceramic Board of 50 cm²x 1.1 mm Pb(FET1): Pb(FET2) = 1:1 1 m 10 m 100 m 1 10 100 1000 PW - Pulse Width - s

[MEMO]

[MEMO]

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